







¹ Institute for Applied Materials

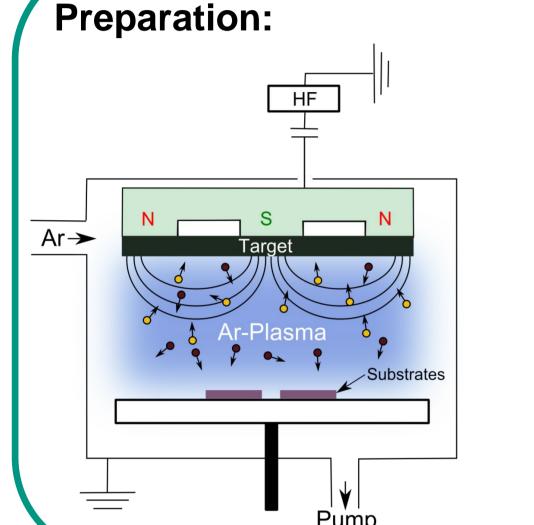
² Karlsruhe Nano Micro Facility (KNMF) Hermann-von-Helmholtz-Platz 1 76344 Eggenstein-Leopoldshafen, Germany.

*Corresponding author: michael.bruns@kit.edu

R.F. Magnetron Sputtered Li-Mn-O Films for Li-Ion Batteries: Combined XPS and ToF-SIMS Characterization

M. Bruns^{1,2,*}, J. Fischer¹, H. Ehrenberg¹, H.J. Seifert¹, S. Ulrich¹

Most of currently available lithium-ion batteries operate with toxic and highly flammable liquid electrolytes bearing risks of leakage, ignitability and undesirable side-reactions. To overcome these problems a very promising approach is the development of all-solid-state-LIBs by means of thin-film technology. Such batteries consist of a solid multilayer stack of cathode, electrolyte and anode thin films of about 3 µm overall thickness [1]. The present study focusses on the surface analytical characterization of environmental friendly Li-Mn-O based thin film cathodes fabricated by means of combined R.F. magnetron sputtering and furnace annealing [2]. ToF-SIMS and XPS allows for quantitative information on the uniformity of the as prepared thin films as well as of the atomic and/or ionic inter-diffusion of the layer constituents at the contact interface (cathode and current collector) during annealing. Special care was taken to widely guarantee atmosphere-contact-free sample transport.



Film deposition by R.F. magnetron sputtering

Substrates: stainless steel discs,

12 mm diam. x 0.5 mm thickness

100 nm Gold Interlayer:

Targets: LiMn₂O₄ (CERAC Inc., USA)

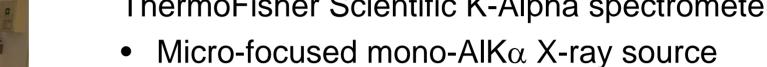
Li₂MnO₂ (MaTecK GmbH, Germany)

Annealing: 100 nm thick films using the *LiMn₂O₄-target*: 30 min at 700 °C in ambient air (~1000 hPa)

> 100 nm thick films using the *Li₂MnO₂ -target*: 30 min at 665 °C under vacuum (5×10⁻³ Pa)

Characterization:

X-ray Photoelectron Spectroscopy (XPS): ThermoFisher Scientific K-Alpha spectrometer



• 1 keV Ar⁺ sputter depth profiles

Time-of-Flight Secondary Mass Spectrometry (ToF-SIMS):

ION-TOF GmbH ToF.SIMS⁵ spectrometer

Bi+, pos. & neg. polarity

2 keV Cs⁺ sputter depth profiles

Atmosphere-contact-free sample handling

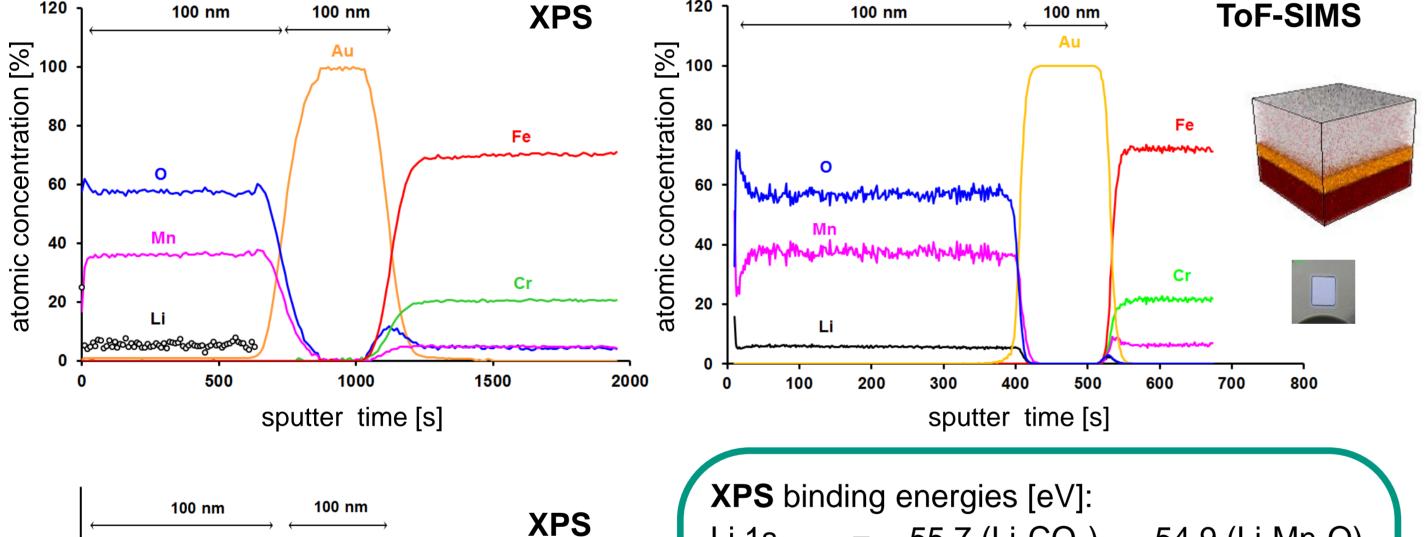


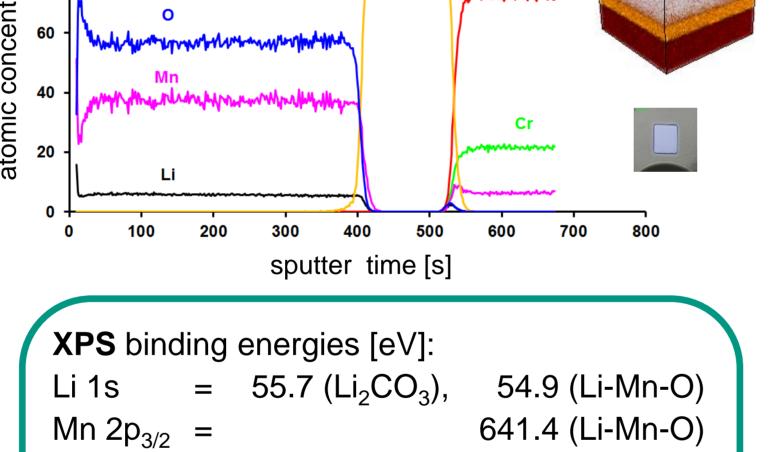
Deposition Parameters 16 Pa Argon, 100 W R.F. power

Li₂MnO₂ - Target

Deposition Parameters 4 Pa Argon, 100 W R.F. power

as deposited





Mn $2p_{3/2} =$ $= 532.7 (Li_2CO_3),$ 529.8 (Li-Mn-O) $= 84.0 (Au^{\circ})$ Au 4f_{7/2} $Fe 2p_{3/2} = 706.8 (Fe^{\circ})$ $Cr 2p_{3/2} = 574.1 (Cr^{\circ})$

ToF-SIMS fragments/ions: MCs⁺ and O₂⁻

<u>%</u> 100 atomic cond 40 20 1500 sputter time [s]

XPS normalized area [a.u.] ૹૹૹૹૹૹ૾ૹૢૹૹૹૹ*ૺ*

sputter time [s]

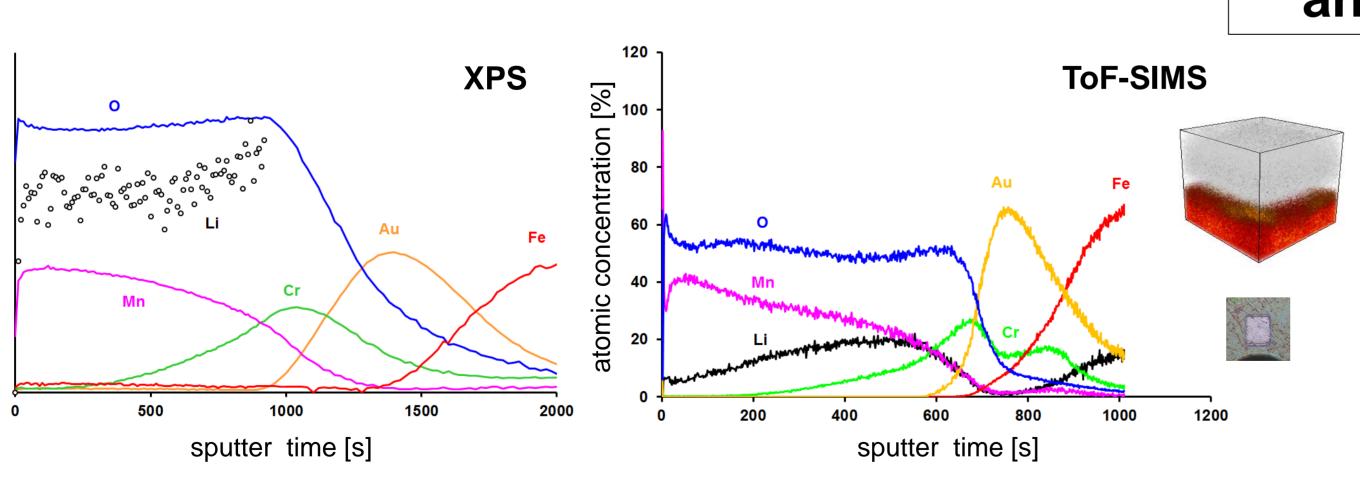
ToF-SIMS 500 sputter time [s]

XPS cross talk: Li 1s, Au $5p_{3/2}$, and Fe 3p Mn $2p_{3/2}$ and Au $4p_{1/2}$ insufficient Li 1s cross section **XPS** detection limit: Li $1s = 0.06 \Leftrightarrow C 1s = 1.00$

→ XPS sputter depth profiles using normalized area → ToF-SIMS sputter depth profiles calibrated by XPS

ToF-SIMS

→ Sharp multilayer interfaces



- → Quantitative depth resolved elemental composition of thin film cathodes, anodes and solid state electrolytes
- film cathode → Influence of ambient air on the topmost surface of the battery active materials

1500

sputter time [s]

annealed **XPS** [a.u.] oncentration normalized 500 1000 1500 sputter time [s] sputter time [s]

1500

XPS

- Combined **ToF-SIMS** and **XPS** measurements can help to improve:
- the adhesion and electrical contact between current collector and electrode materials
- the solid electrolyte interface (SEI) and artificial SEIs
- protective coatings to prevent Mn²⁺-dissolution into acidic liquid electrolytes
- Li⁺ diffusion barriers, Li⁺ transport processes, and corrosion behavior

Conclusions

[a.u.]

area

normalized

Combined ToF-SIMS and XPS allows for quantitative information on the uniformity of the as prepared thin films as well as on diffusion processes during annealing

Detailed information on elemental diffusion processes between substrate, interface and thin

- The depth profiles give hints on reaction layers at the thin film surface and the substrate to cathode interface
- Post mortem analysis for investigation of the degradation mechanisms after electrochemical cycling are possible

References

[1] J.B. Bates, N.J. Dudney, B. Neudecker, A. Ueda, C.D. Evans, Solid State Ionics, 135 (2000) 33-45. [2] J. Fischer, C. Adelhelm, T. Bergfeldt, K. Chang, C. Ziebert, H. Leiste, M. Stüber, S. Ulrich, D. Music, B. Hallstedt, H.J. Seifert, Thin Solid Films, 528 (2013) 217-223.

Acknowledgement

The authors gratefully acknowledge the financial support by the priority program SPP1473 WeNDeLIB of the German Science Foundation (DFG) in the project UL 181/3-1.